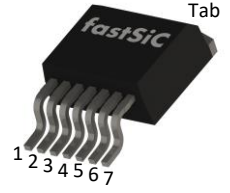
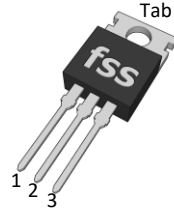
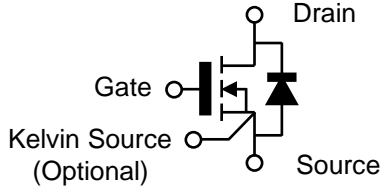


**Silicon Carbide MOSFET**

650V, 65mΩ SiC MOSFET – Falcon Series



**Product Information:**



**TO-220-3L**

**TOLL**

**TO-263-7L**

**Features**

- Optimized  $R_{DS(on)}$  with Rapid Switching Behavior
- Compatible with Standard Gate Drivers
- Clean Kelvin-Source Switching Pin-out
- High Avalanche Endurance Capability
- Optimized for High Power Density Applications
- RoHS Compliant and Halogen Free
- Validated Based on AEC-Q101 Automotive Qualified

Terminal	Packaging Type		
	TO-220-3L	TOLL	TO-263-7L
Gate	1	1	1
Drain	2, Tab	Tab	Tab
Source	3	3,4,5,6,7,8	3,4,5,6,7
Kelvin Source	--	2	2

**Benefits**

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

**Potential Applications**

- Switching Mode Power Supply
- PFC & DC/DC Converter
- EV Charging Station
- UPS
- Renewable Energy
- Power Inverter & Motor Driver

**Key Performance Parameters**

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS @ T_{j(max)}}$	700	V
Recommended Gate-Source Turn-On Voltage	$V_{GS}$	15~18	
Drain-Source On-State Resistance	$R_{DS(on)}$	65	mΩ
Continuous Drain Current	$I_D$	44	A
Pulse Drain Current	$I_{D, pulse}$	120	
Power Dissipation	$P_{tot}$	214	W
Avalanche Energy	$E_{AS}$	500	mJ
Gate Charge	$Q_G$	69	nC
Output Capacitive Charge	$Q_{oss}$	66	
Junction & Storage Temperature	$T_j, T_{stg}$	-55 to 175	°C

Part Number	Package	Marking
FF06060CA	TO-220-3L	FF06060A
FF06060FA	TOLL	FF06060A
FF06060J-7A	TO-263-7L	FF06060A

For further information about comparable products, please contact ([www.fastsic.com](http://www.fastsic.com)).

**Maximum Ratings: ( $T_j = 25^\circ\text{C}$ , unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Voltage	$V_{DSS}$	650	--	--	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$
Continuous Drain Current	$I_D$	--	--	44 32	A	$V_{GS}=18\text{V}, T_c=25^\circ\text{C}$ $V_{GS}=18\text{V}, T_c=100^\circ\text{C}$
Pulse Drain Current	$I_{D,pulse}$	--	--	120		Per Fig. 13
Continuous Body Diode Current	$I_S$	--	--	30		$V_{GS}=0\text{V}, T_c=25^\circ\text{C}$
Avalanche Energy, Single Pulse	$E_{AS}$	--	--	500	mJ	$L=25\text{mH}$
Operate Gate Source Voltage	$V_{GS,op}$	-8~0	--	15~18	V	Recommended operating values
Transient Gate Source Voltage	$V_{GS,tran.}$	-10	--	22		Transient operating limit (AC $f > 1\text{Hz}$ , pulse width $< 100\text{ns}$ )
Power Dissipation	$P_{tot}$	--	--	214	W	$T_c=25^\circ\text{C}$
Junction Temperature	$T_j$	-55	--	175	°C	--
Storage Temperature	$T_{stg}$	-55	--	175		
Soldering Temperature	$T_L$	--	--	260		

**Electrical Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>DC Characteristics (at <math>T_j = 25^\circ\text{C}</math>, unless otherwise specified)</b>						
Drain-source Breakdown Voltage	$V_{(BR)DSS}$	650 --	-- 700	-- --	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=175^\circ\text{C}$
Drain-Source On-State Resistance	$R_{DS(on)}$	-- --	65 84	80 --	mΩ	$V_{GS}=18\text{V}, I_D=15\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=18\text{V}, I_D=15\text{A}, T_j=175^\circ\text{C}$
Gate-Source Threshold Voltage	$V_{th}$	--	2.5	--	V	$V_{GS}=V_{DS}, I_D=20\text{mA}$
Zero Gate Voltage Drain Current	$I_{DSS}$	--	$<1$	60	μA	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_j=25^\circ\text{C}$
Gate-Source Leakage Current	$I_{GSS}$	--	--	100	nA	$V_{GS}=18\text{V}, V_{DS}=0\text{V}$
Body Diode Forward Voltage	$V_{SD}$	-- --	3.4 2.9	-- --	V	$V_{GS}=0\text{V}, I_S=7\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_S=7\text{A}, T_j=175^\circ\text{C}$
<b>AC Characteristics (at <math>T_j = 25^\circ\text{C}</math>, unless otherwise specified)</b>						
Input Capacitance	$C_{iss}$	--	1499	--	pF	$V_{DS}=400\text{V}, V_{GS}=0\text{V},$ $f=250\text{kHz}, V_{AC}=25\text{mV}$
Output Capacitance	$C_{oss}$	--	113	--		
Reverse Capacitance	$C_{rss}$	--	17	--		
Effective Output Capacitance, energy related	$C_{o(er)}^1$	--	124	--		
Effective Output Capacitance, time related	$C_{o(tr)}^2$	--	164	--		
$C_{oss}$ Stored Energy	$E_{oss}$	--	10	--		
Output Capacitive Charge	$Q_{oss}$	--	66	--	nC	
Internal Gate Resistance	$R_{G,int.}$	--	2.2	--	Ω	$f=1\text{MHz}, V_{AC}=25\text{mV}$

<sup>1</sup>  $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400V.

<sup>2</sup>  $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400V.

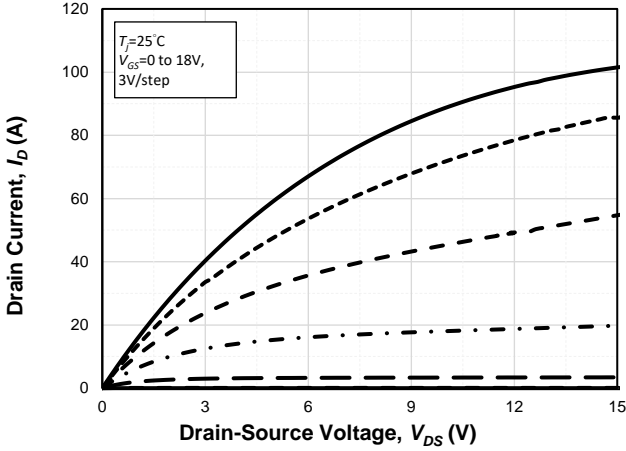
**Switching Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Gate Characteristics</b>						
Gate to Source Charge	$Q_{GS}$	--	11	--	nC	$V_{DS}=400V, V_{GS}=0V/15V, I_D=15A$
Gate to Drain Charge	$Q_{GD}$	--	34	--		
Total Gate Charge	$Q_G$	--	69	--		
<b>Inductive Load</b>						
Turn On Delay Time	$t_{d(on)}$	--	33	--	ns	$V_{DS}=400V,$ $I_D=13A,$ $V_{GS}=-3/+15V,$ $R_{G(ext.)}=2.7\Omega$ External SiC Diode as an FWD
Rise Time	$t_r$	--	28	--		
Turn Off Delay Time	$t_{d(off)}$	--	21	--		
Fall Time	$t_f$	--	11	--		
Turn On Switching Energy	$E_{on}$	--	87	--	$\mu J$	
Turn Off Switching Energy	$E_{off}$	--	11	--		
<b>Resistive Load</b>						
Turn On Delay Time	$t_{d(on)}$	--	18	--	ns	$V_{DS}=400V,$ $I_D=13.3A, V_{GS}=-3/+15V,$ $R_G=2.7\Omega, R_L=30\Omega$
Rise Time	$t_r$	--	11	--		
Turn Off Delay Time	$t_{d(off)}$	--	23	--		
Fall Time	$t_f$	--	24	--		
<b>Body Diode Characteristics</b>						
Reverse Recovery Charge	$Q_{rr}$	--	42	--	nC	$V_{GS}=0V,$ $I_S=13A, V_{DS}=400V,$ $di/dt=476A/\mu s$ * $Q_{rr}$ herein excluded the $Q_{oss}$ value.
Reverse Recovery Time	$t_{rr}$	--	15	--	ns	
Peak Reverse Recovery Current	$I_{rrm}$	--	4.3	--	A	

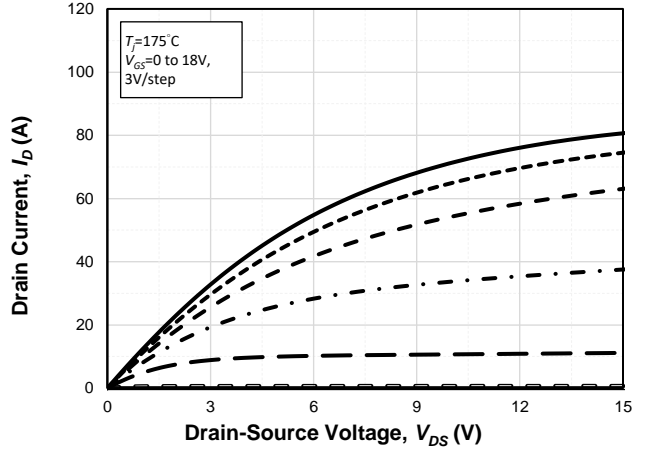
**Thermal Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction-case	$R_{th-jc}$	--	0.7	--	K/W	--
Thermal Impedance, junction-ambient	$R_{th-ja}$	--	40	--		Device on PCB, with 6 cm <sup>2</sup> of cooling area

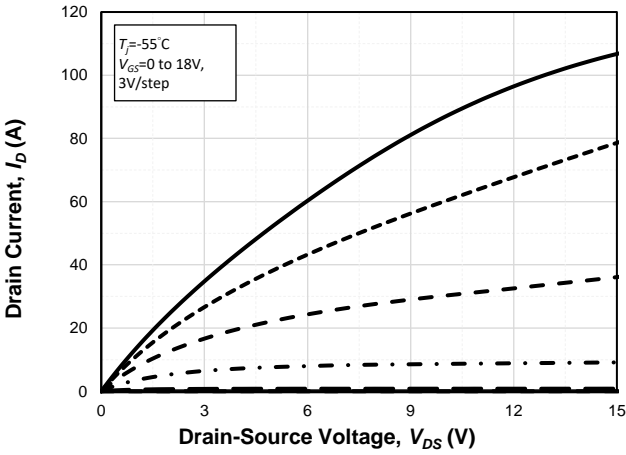
**Electrical Characteristics Diagrams**



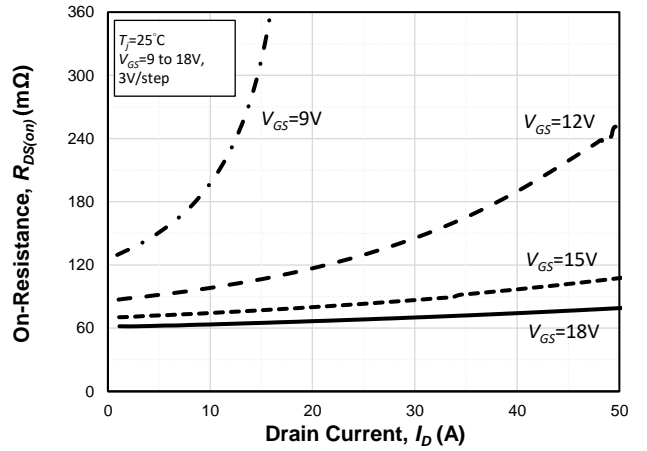
**Fig. 1 Typical Output Characteristics at  $T_j=25^\circ\text{C}$**



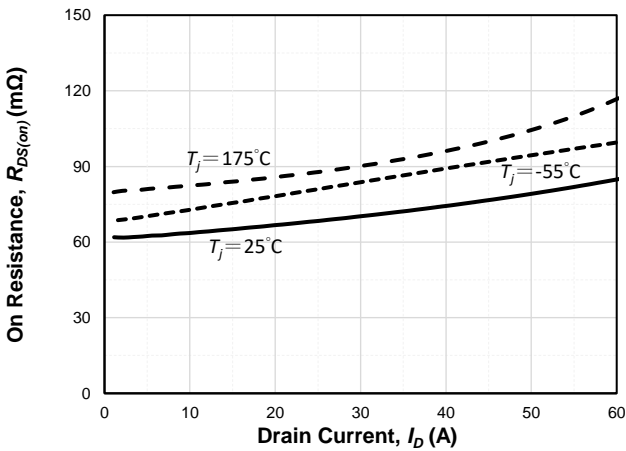
**Fig. 2 Typical Output Characteristics at  $T_j=175^\circ\text{C}$**



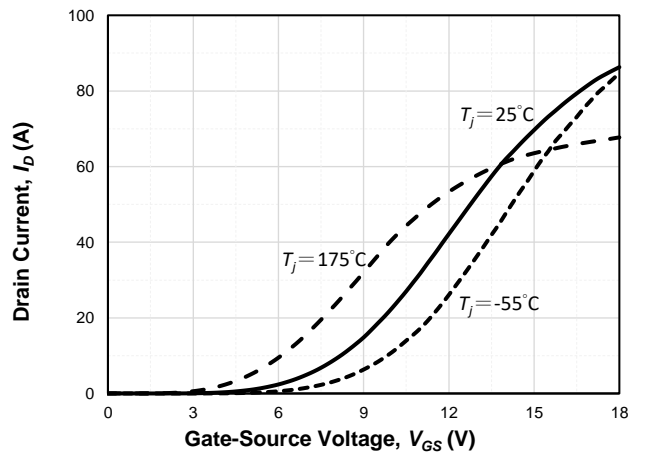
**Fig. 3 Typical Output Characteristics at  $T_j=-55^\circ\text{C}$**



**Fig. 4 Typ.  $R_{DS(on)}$  vs.  $I_D$  with Various  $V_{GS}$**

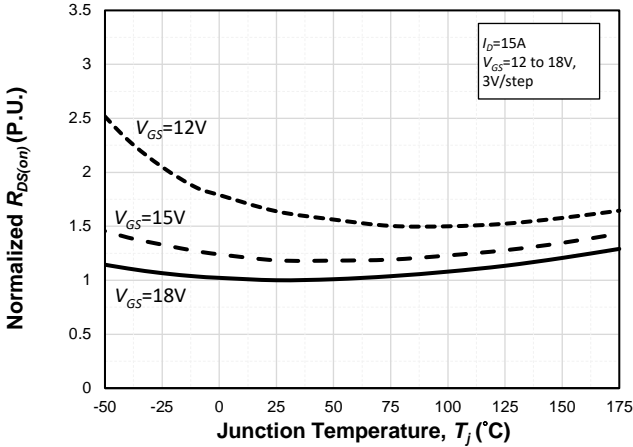


**Fig. 5 Typ.  $R_{DS(on)}$  vs.  $I_D$  with Various  $T_j$ ,  $V_{GS}=18\text{V}$**

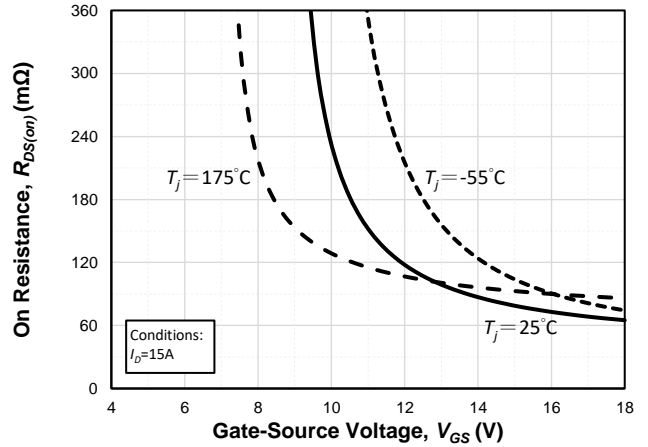


**Fig. 6 Typ.  $I_D$  vs.  $V_{GS}$  with Various  $T_j$ ,  $V_{DS}=10\text{V}$**

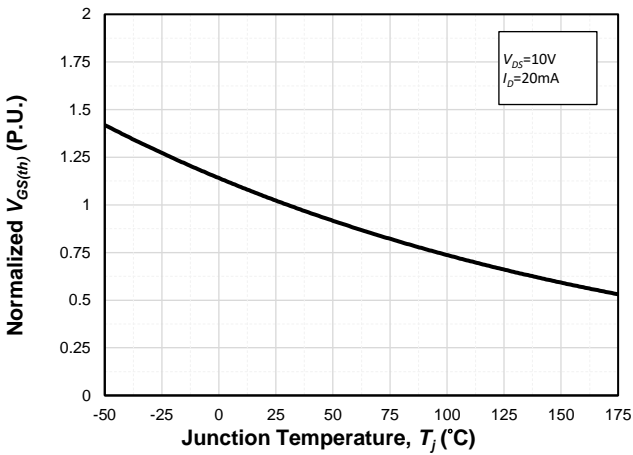
**Electrical Characteristics Diagrams**



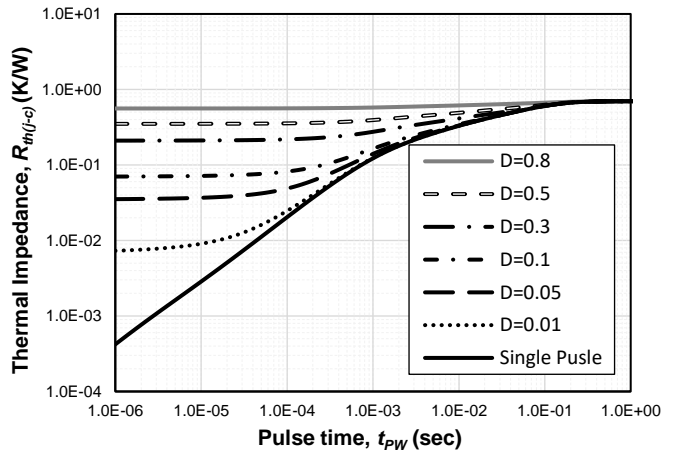
**Fig. 7 Normalized  $R_{DS(on)}$  vs.  $T_j$  with Various  $V_{GS}$**



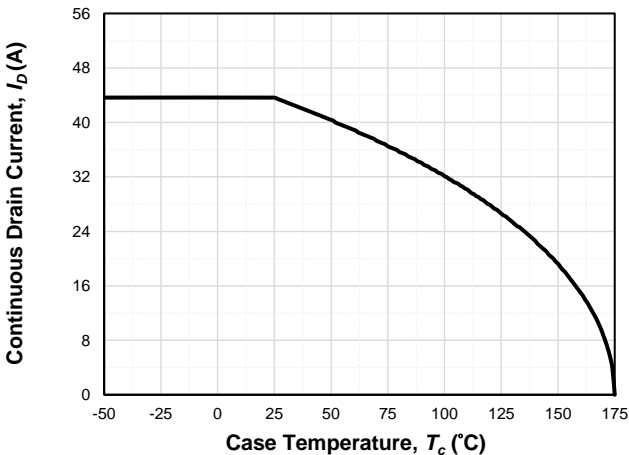
**Fig. 8 Typ.  $R_{DS(on)}$  vs.  $V_{GS}$  with Various  $T_j$**



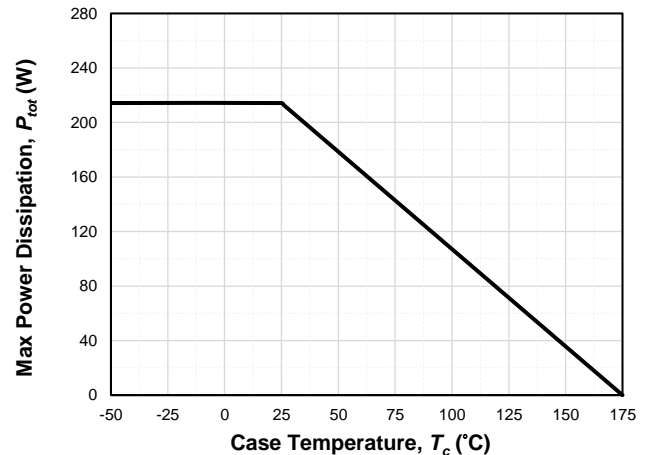
**Fig. 9 Normalized  $V_{th}$  vs.  $T_j$**



**Fig. 10 Typ. Transient Thermal Impedance  $R_{th-jc}$**

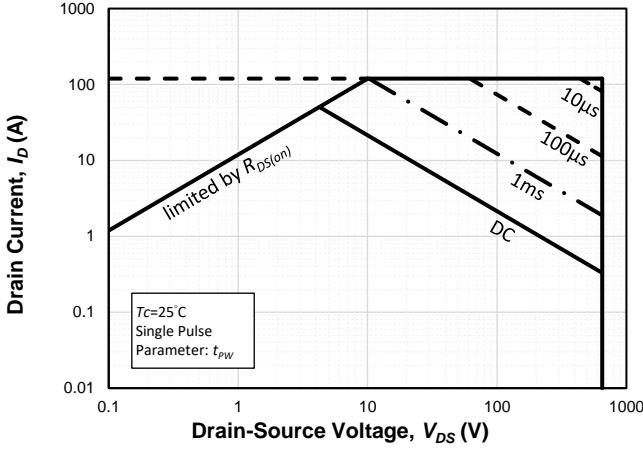


**Fig. 11 Continuous  $I_D$  De-rating at  $V_{GS}=18V, T_j \leq 175^\circ C$**

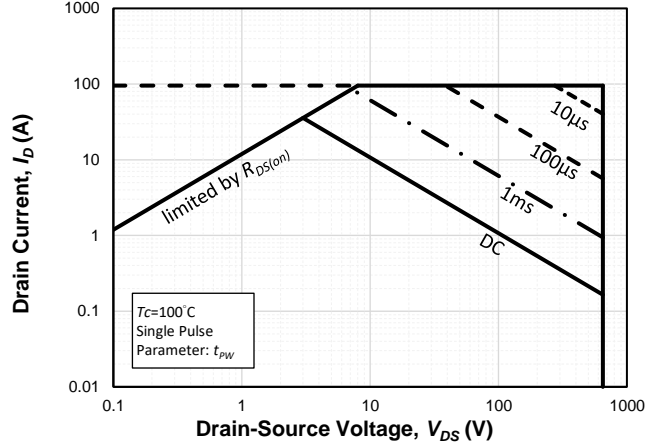


**Fig. 12 Power Dissipation at  $V_{GS}=18V, T_j \leq 175^\circ C$**

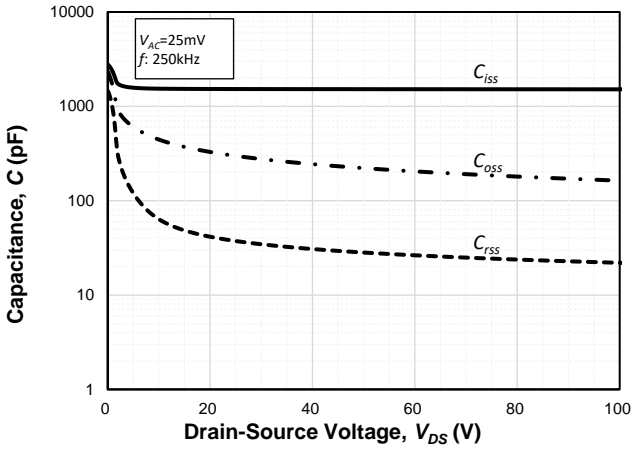
**Electrical Characteristics Diagrams**



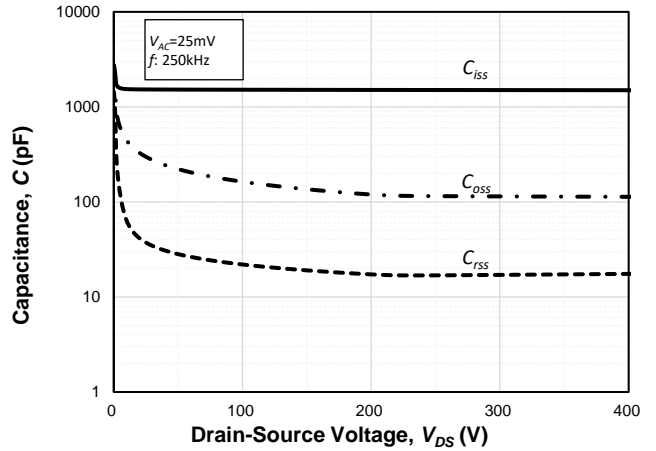
**Fig. 13 Safe Operating Area at  $T_c=25^\circ\text{C}$**



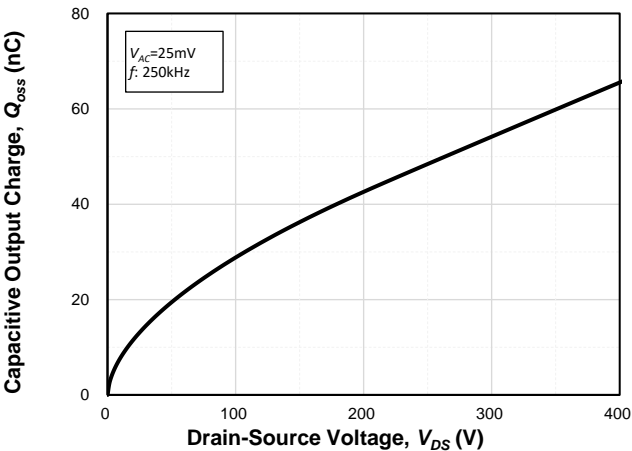
**Fig. 14 Safe Operating Area at  $T_c=100^\circ\text{C}$**



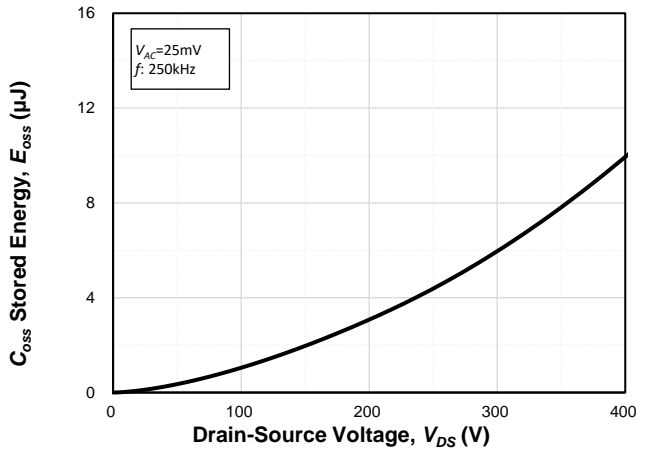
**Fig. 15 Typ. Capacitance vs.  $V_{DS}$  at  $f_{sw}=250\text{kHz}$ ,  $V_{DS}\leq 100\text{V}$**



**Fig. 16 Typ. Capacitance vs.  $V_{DS}$  at  $f_{sw}=250\text{kHz}$ ,  $V_{DS}\leq 400\text{V}$**



**Fig. 17 Typ. Capacitive Output Charge at  $f_{sw}=250\text{kHz}$**



**Fig. 18 Typ.  $C_{oss}$  Stored Energy at  $f_{sw}=250\text{kHz}$**

**Electrical Characteristics Diagrams**

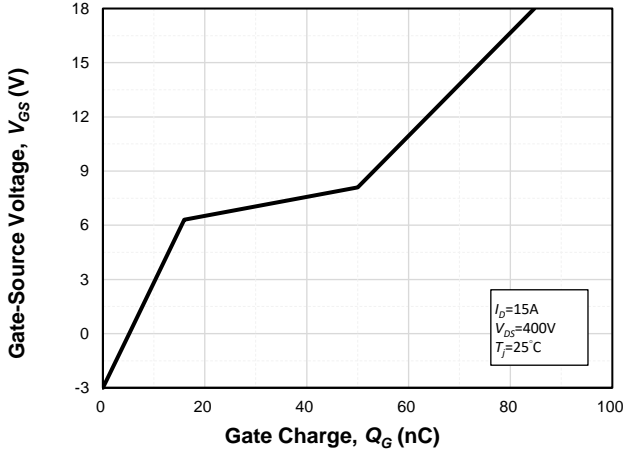


Fig. 19 Typ. Gate Charge at  $V_{DS}=400V$ ,  $I_D=15A$

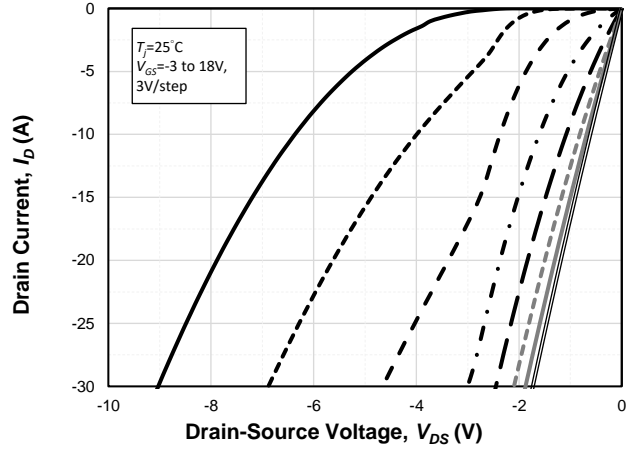


Fig. 20 Typical Forward Characteristics of Reverse Conduction at  $T_J=25^\circ C$

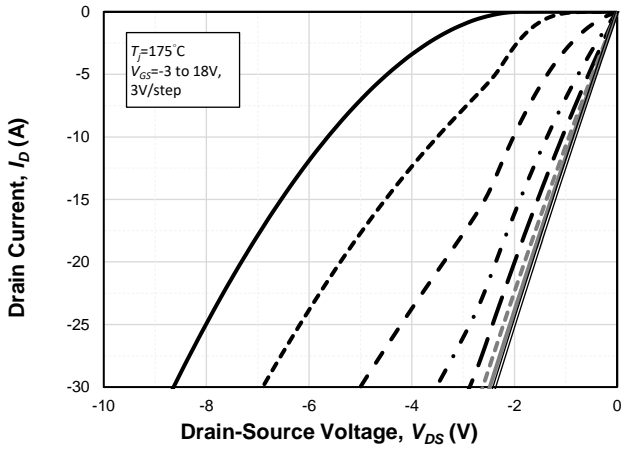


Fig. 21 Typical Forward Characteristics of Reverse Conduction at  $T_J=175^\circ C$

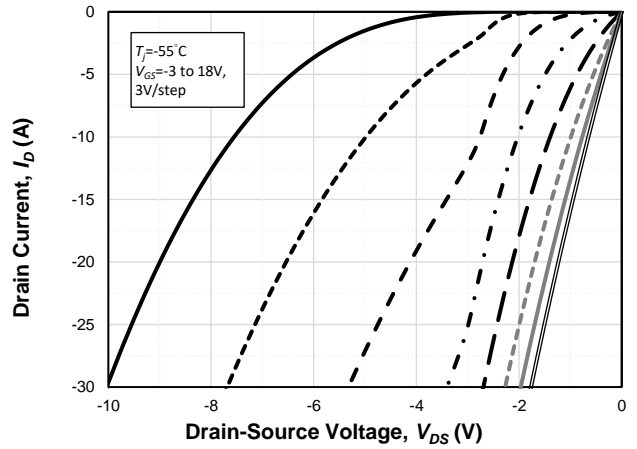


Fig. 22 Typical Forward Characteristics of Reverse Conduction at  $T_J=-55^\circ C$

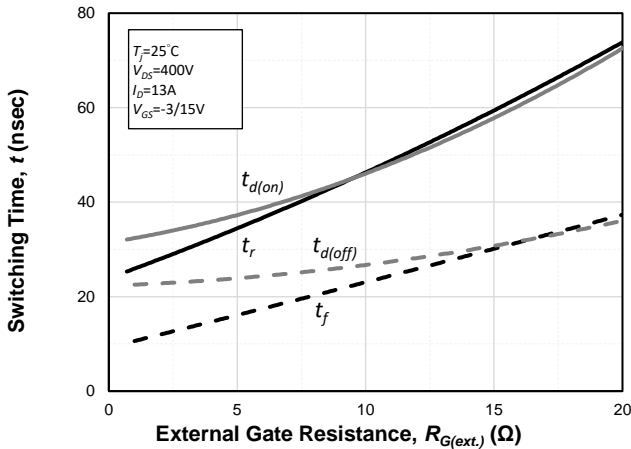


Fig. 23 Typ. Switching Time vs.  $R_{G(ext.)}$

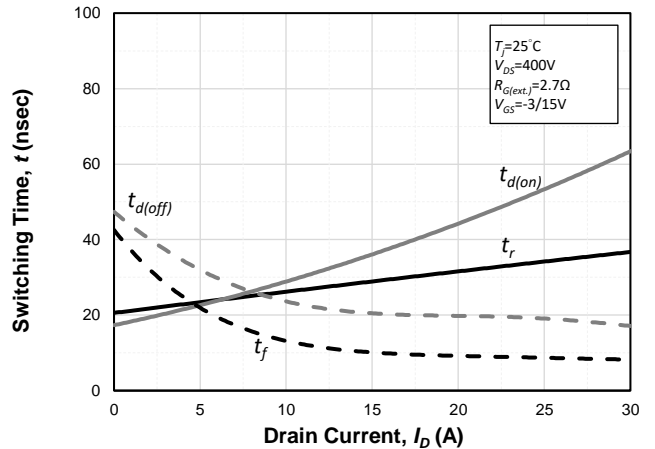


Fig. 24 Typ. Switching Time vs.  $I_D$

**Electrical Characteristics Diagrams**

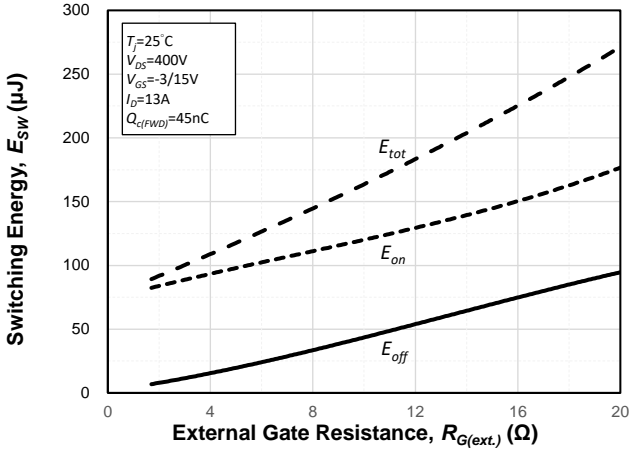


Fig. 25 Typ. Switching Energy vs.  $R_{G(ext.)}$

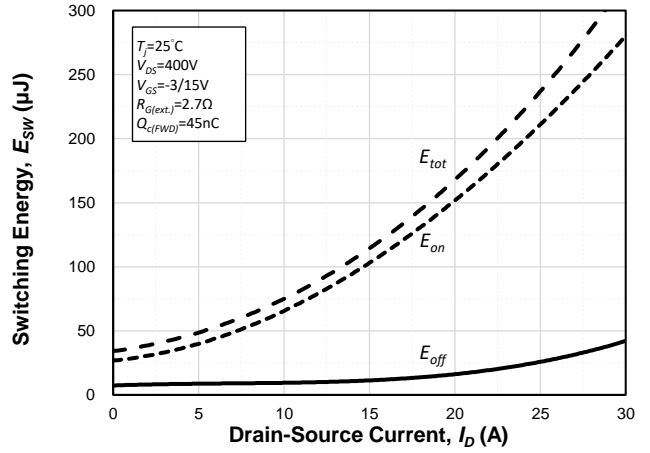
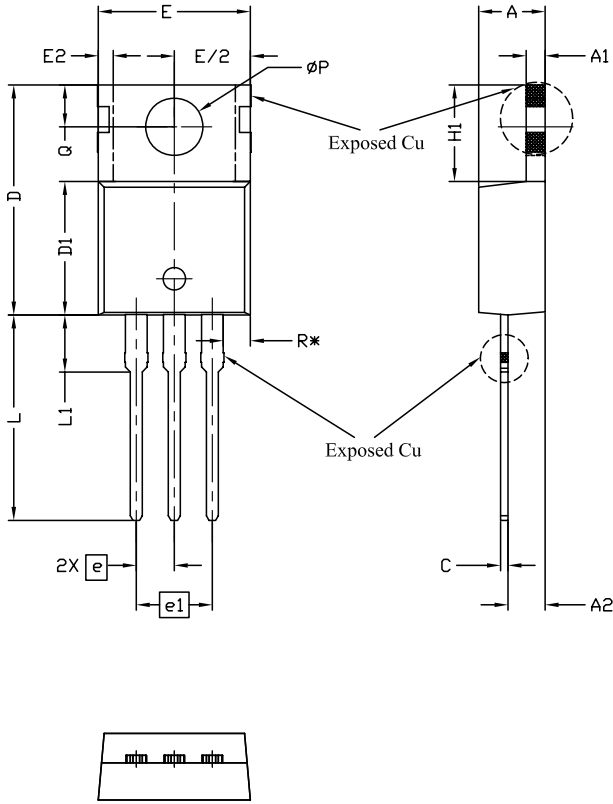


Fig. 26 Typ. Switching Energy vs.  $I_D$



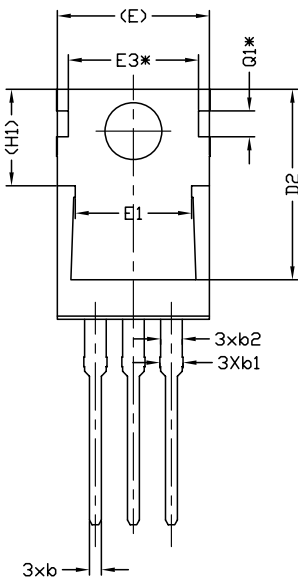
**Package Outline (TO-220-3L)**



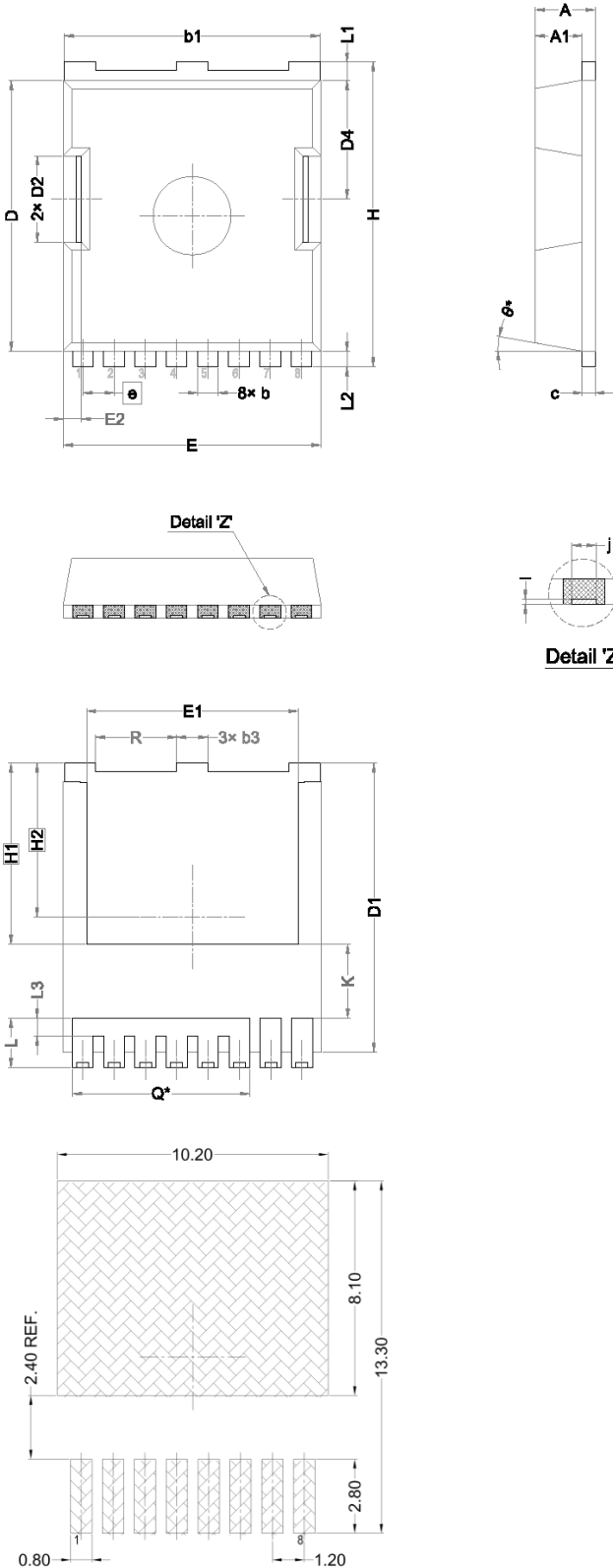
Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	4.24	4.44	4.64
A1	1.15	1.27	1.40
A2	2.30	2.48	2.70
b	0.70	0.80	0.90
b1	1.20	1.55	1.75
b2	1.20	1.45	1.70
c	0.40	0.50	0.60
D <sup>(2)</sup>	14.70	15.37	16.00
D1	8.82	8.92	9.02
D2 <sup>(3)</sup>	12.43	12.73	12.83
E <sup>(2), (3)</sup>	9.96	10.16	10.36
E1 <sup>(3)</sup>	6.86	7.77	8.89
E2 <sup>(4)</sup>	--	--	0.76
E3*	8.70 REF.		
e	2.54 BSC.		
e1	5.08 BSC.		
H1 <sup>(3), (4)</sup>	6.30	6.45	6.60
L	13.47	13.72	13.97
L1	3.60	3.80	4.00
ØP	3.75	3.84	3.93
Q	2.60	2.80	3.00
Q1*	1.73 REF.		
R*	1.82 REF.		

**Note:**

1. Slot required; notch may be rounded.
2. Dimension D & E do not include mold flash. Mold flash shall not exceed 0.127mm pre side. These dimensions are measure at the outermost extreme of the plastic body.
3. Thermal pad contour optional within dimensions E, H1, D2 & E1.
4. Dimension E2 & H1 define a zone where stamping and singulation irregularities are allowed.
5. "\*" is for reference.



**Package Outline (TOLL, MO-299B)**



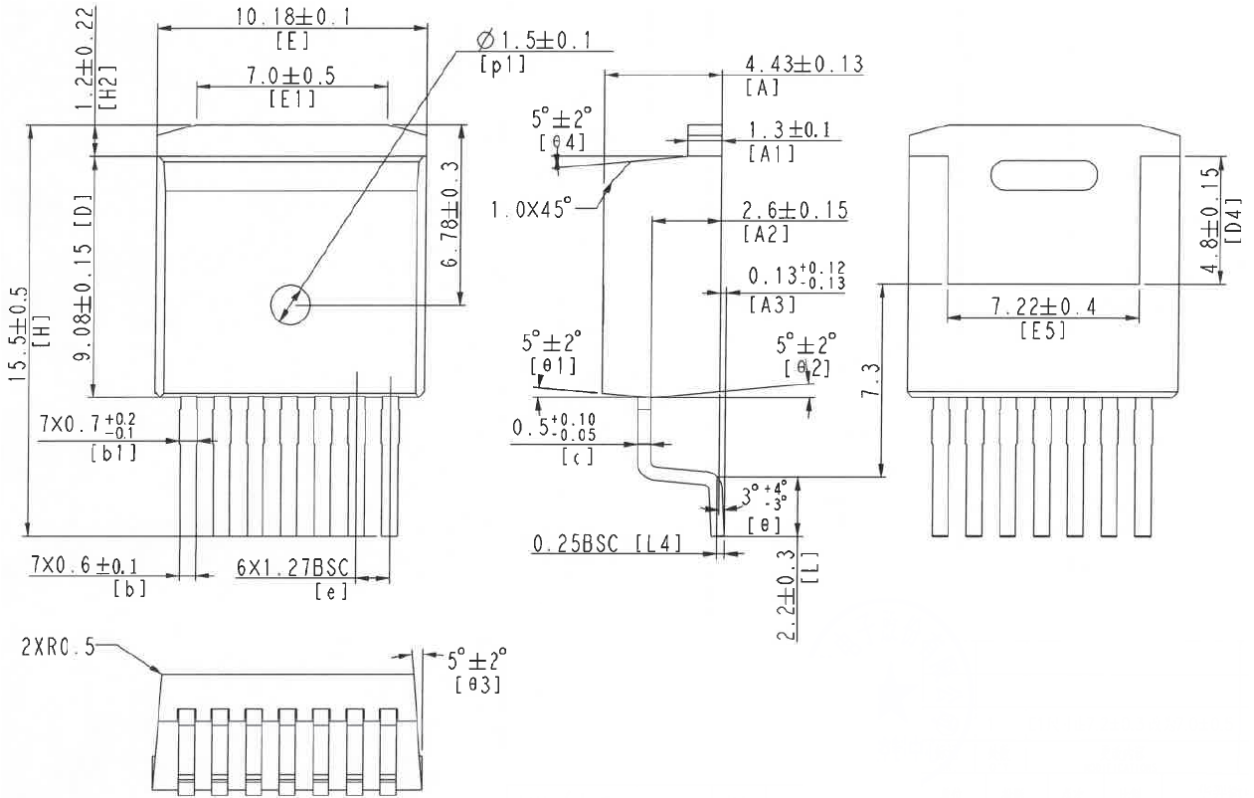
Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.28	10.38	10.48
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D4	4.45	4.55	4.65
E	9.80	9.90	10.00
E1	8.00	8.10	8.20
E2	0.60	0.70	0.80
e	1.20 BSC.		
H	11.58	11.68	11.78
H1	6.95 BSC.		
H2	5.89 BSC.		
i	0.10 REF.		
j	0.46 REF.		
K	2.80 REF.		
L	1.40	1.90	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.30	0.70	0.80
N	8		
Q	6.80 REF.		
R	3.00	3.10	3.20
θ	10° REF.		

**Note:**

1. Dimensions do not inclusive burrs and mold flash.
2. "\*" is for reference.

**Land Pattern (Only for reference)**

**Package Outline (TO-263-7L)**



## Revision History

Date	Revision	Changes
23.04	Preliminary	1 <sup>st</sup> issue
23.04	Preliminary	Update dynamic characteristics
23.05	Preliminary	Revise P/N
24.04	Preliminary	Minor change
24.11	Preliminary	Update pad layout

## Important Note (Disclaimer)

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